

<b>Notice of References Cited</b>		Application/Control No. 10/551,130	Applicant(s)/Patent Under Reexamination KISHIOKA, TAKAHIRO	
		Examiner Cynthia Hamilton	Art Unit 1795	Page 1 of 2

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
+	A	US-5,498,514	03-1996	Nakao et al.	430/512
*	B	US-6,168,908	01-2001	Suzuki et al.	430/325
*	C	US-4,130,424	12-1978	Feit et al.	430/271.1
*	D	US-4,469,832	09-1984	Singer et al.	524/160
*	E	US-6,399,269	06-2002	Mizutani et al.	430/270.1
*	F	US-6,410,209	06-2002	Adams et al.	430/311
*	G	US-2003/0008237	01-2003	Pavelchek et al.	430/271.1
*	H	US-7,038,328	05-2006	Enomoto et al.	257/791
*	I	US-2005/0181299	08-2005	Trefonas et al.	430/270.1
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP-58-48048 A	03-1983	Japan	Hibino et al	
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	AN 1983:430757, ACS on STN database, file CAPLUS, English abstract of JP 58048048 a, Hibino et al, entered in STN 12 May 1984 and RN 86249-19-6 cited and from REGistry file, 4 pages.			
	V	DERWENT-ACC-NO: 1983-40723K, English abstract of JP 58048048 A, Hibino et al, Derwent Information LTD, from Derwent Week- 198843, 2 pages printed December 1, 2009 from DERWENT file of East database.			
	W	Silverstein, Journal of CHemical Education, July 2000, volum 77, No. 7 pages 849-850.			
	X	Strong acid-Wikipedia, The free encyclopedia down loaded December 1, 2009 3 pages.			

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/551,130		Applicant(s)/Patent Under Reexamination KISHIOKA, TAKAHIRO	
	Examiner Cynthia Hamilton		Art Unit 1795	Page 2 of 2

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Ding et al "Optimization of Bottom antireflective coating materials for dual damascene process", Advances in Resist Technology and Processing, XVII, Francis M. Houlihand, Ed, Proceedings of SPIE , VOL. 3999 (no month given ) year 2000 pages 910-918.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.